

NISTTech

Tip-Mounted Nanowire Light Source Instrumentation

Achieve unique functionality for nanostructure growing, etching, and characterization

Abstract

The invention is to attach a unique light source to a scanning probe microscopy tip to achieve unique functionality for nanostructure growth, etching, and characterization. The light source is a nanowire light emitting diode (LED) or nanowire laser. The most common mode would be attachment to an atomic force microscopy (AFM) tip, but other scanning probe instrumentation could also be combined with nanowire light source.

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References

- Serial #13/009,300
- Docket: 10-008

Status of Availability

This invention is available for licensing exclusively or non-exclusively in any field of use.

Last Modified: 12/29/2010